Se	arch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/709,784	CHAN ET AL.
Examiner	Art Unit
Don P. Le	2819

SEARCHED					
Class	Subclass	Date	Examiner		
326	26, 27, 82, -86, 101- 103	5/5/2005	DL		
	:				
•					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
326	27, 83	5/12/2005	DL		
326	103	5/12/2005	DL		

(INCLUDIN	G SEARCH	STRATEGY	)
		DATE	EXMR
east		5/12/2005	DL
		•	
	;		<del>.</del>
			·